

AMENDMENTS TO THE CLAIMS

IN THE CLAIMS:

This listing of claims will replace all prior versions and listings of claims in the application. Please amend the claims as follows.

1-73. (canceled)

74. (currently amended) A substrate including an anodized coating, said coating having a thickness quality of about 1.3 times better than a coating thickness quality of an anodized substrate made without a coating thickness monitor communicating with a controller, said coating thickness monitor including:

a) at least one radiation source directed at at least a portion of the anodized substrate;

b) at least one probe for capturing at least a portion of the radiation reflected and refracted by the anodized coating on the anodized substrate, the captured radiation being at least a portion of the radiation directed at the anodized substrate from said radiation source; and

c) at least one detector in communication with said at least one probe, said at least one detector capable of processing the captured radiation to allow a determination of at least the thickness of the anodized coating on the substrate.

75. (currently amended) The substrate of claim 74 further including an additional coating on said anodized coating.

76. (currently amended) A substrate including an anodized coating, said coating having a thickness quality of at least about 1.3 times better and a thickness consistency of about 1.6 ~~time~~ times better thereby having a thickness quality x consistency product at least about 2 times better than a coating thickness quality x consistency product of an anodized substrate made without a coating thickness monitor communicating with a controller, said coating thickness monitor including:

a) at least one radiation source directed at at least a portion of the anodized substrate;

b) at least one probe for capturing at least a portion of the radiation reflected and refracted by the anodized coating on the anodized substrate, the captured radiation being at least a portion of the radiation directed at the anodized substrate from said radiation source; and

c) at least one detector in communication with said at least one probe, said at least one detector capable of processing the captured radiation to allow a determination of at least the thickness of the anodized coating on the substrate.

77. (currently amended) A substrate including an anodized coating and an additional coating on said anodized coating, said anodized coating having a thickness quality of at least about 1.3 times better and a thickness consistency of about 1.6 ~~time~~ times better thereby having a thickness quality x consistency product at least about 2 ~~time~~ times better than a coating thickness quality x consistency product of an anodized substrate made without a coating thickness monitor communicating with a controller, said coating thickness monitor including:

a) at least one radiation source directed at at least a portion of the anodized substrate;

b) at least one probe for capturing at least a portion of the radiation reflected and refracted by the anodized coating on the anodized substrate, the captured radiation being at least a portion of the radiation directed at the anodized substrate from said radiation source; and

c) at least one detector in communication with said at least one probe, said at least one detector capable of processing the captured radiation to allow a determination of at least the thickness of the anodized coating on the substrate.

Please add the following new claims:

78. (new) The substrate of claim 74 wherein the anodized coating is made with a coating thickness monitor in communication with a controller.

79. (new) The substrate of claim 75 wherein the anodized coating is made with a coating thickness monitor in communication with a controller.

80. (new) The substrate of claim 76 wherein the anodized coating is made with a coating thickness monitor in communication with a controller.

81. (new) The substrate of claim 77 wherein the anodized coating is made with a coating thickness monitor in communication with a controller.

82. (new) The substrate of claim 78, wherein the coating thickness monitor includes an additional radiation source.

83. (new) The substrate of claim 79, wherein the coating thickness monitor includes an additional radiation source.

84. (new) The substrate of claim 80, wherein the coating thickness monitor includes an additional radiation source.

85. (new) The substrate of claim 81, wherein the coating thickness monitor includes an additional radiation source.